

Notice of References Cited	Application/Control No. 10/781,115	Applicant(s)/Patent Under Reexamination CRANDALL ET AL.	
	Examiner Anthony Weier	Art Unit 1761	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-5,955,134	09-1999	Nishimura et al.	426/489
	D	US-3,160,569	12-1964	NOBUO TOYAMA	435/264
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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